# IEC QUALITY ASSESSMENT SYSTEM (IECQ)

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# IECQ Certificate of Approval
# Independent Testing Laboratory

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|---|---|---|---|---|---|
| **IECQ Certificate No.:** | **IECQ-L ULTW 18.0001** | **Issue No.:** | **8** | **Status:** | **Current** |
| Supersedes: | IECQ-L ULTW 18.0001 Issue 7 | **Issue Date:** | **2025/03/23** | **Org Issue:** | **2018/05/30** |
| CB Reference No.: | 20002839 ITL | **Expiration:** | **2027/05/29** | | |

**Winstek Semiconductor Co., Ltd. Reliability and Failure Analysis Laboratory**
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The organization, facilities and procedures have been assessed by the IECQ Certification Body in accordance with IECQ 03-1 and IECQ 03-6 for issuance of this certificate and found to be in conformity with the applicable requirements of the IECQ Independent Testing Laboratory Assessment Program Requirements Scheme and in respect of ISO/IEC 17025:2017 for the testing of component product under the IECQ.

**Scope:**
**Reliability Testing and Failure Analysis of semiconductor IC, electronic components.**
**See attached schedule.**

-- Attached Schedule: IECQ-L_ULTW_20002839 ITL. Schedule 03-23-25.pdf --

**Approved by Certification Body (CB): DQS Group - DQS Taiwan Inc.**

8F, 23, Yuan Huan West Road,
Feng Yuan Dist., Taichung City
Taiwan

Authorized person:
**Bob CHEN**

The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.
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-- Attached Translation: - None --

# Schedule of Scope to Certificate of Approval

## Independent Testing Laboratory

**IECQ Certificate No.: IECQ-L ULTW 18.0001**

**CB Certificate No.: 20002839 ITL**



# Appendix-1 (20002839 ITL)
# Schedule of Scope to Certificate of Approval

| Tests | Standards/Methods |
|---|---|
| Electrostatic Discharge test (ESD-CDM ) | ANSI/ESDA/JEDEC JS-002<br>AEC-Q100-011 |
| Electrostatic Discharge test (ESD-HBM/MM) | MIL-STD-883 Method 3015.8(HBM),<br>ANSI/ESDA/JEDEC JS-001<br>AEC-Q100-002(HBM)<br>JESD22-A115 |
| Electrostatic Discharge test (Latch-up) | JESD78<br>AEC-Q100-004 |
| High Temp Operating Life (HTOL) | JESD22-A108<br>AEC-Q100-008(ELFR) |
| Precondition test / Moisture Sensitivity Level (MSL) | IPC/JEDEC J-STD-020<br>JESD22-A113 |
| Reflow | IPC/JEDEC J-STD-020 |
| High Temperature Storage test (HTST) | JESD22-A103 |
| Low Temperature Storage test (LTST) | JESD22-A119<br>MIL-STD-810 Method 502.7 |
| Accelerated Moisture Resistance-Unbiases (Unbiased HAST) | JESD22- A118 |
| Highly Accelerated Stress test (HAST) | JESD22- A110 |
| Pressure Cooker test (PCT) | JESD22-A102 |
| Temperature Cycle test (TC) | JESD22-A104 |
| Temperature and Humidity test (THT) | JESD22-A101 |

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# Schedule of Scope to Certificate of Approval

## Independent Testing Laboratory

### IECQ Certificate No.: IECQ-L ULTW 18.0001

### CB Certificate No.: 20002839 ITL

**Schedule Number: IECQ-L ULTW 18.0001-S** **Rev No.:** 8 **Revision Date:** 2025/03/23 **Page** 2 **of** 2

| Tests | Standards/Methods |
|---|---|
| Temperature and Humidity with Bias test (THB) | JESD22-A101 |
| Surface Mount Technology (SMT) | IPC/JEDEC J-STD-020<br>IPC-A-610<br>IPC-7525 |
| Scanning Electron Microscope (SEM) | B-QA-LAB0-CM-09 |
| Energy-Dispersive Spectroscopy (EDS) | B-QA-LAB0-CM-09 |
| Scanning Acoustic Microscopy (SAM) | B-QA-LAB0-OI-17 |
| Atomic Force Microscope (AFM) | B-QA-LAB0-OI-14 |
| X-ray | B-QA-LAB0-OI-18 |
| Sample Preparation | B-QA-LAB0-OI-21 |

Technical Reviewer of DQS: Paul Yang Date: 03/23/2025

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Paul Yang